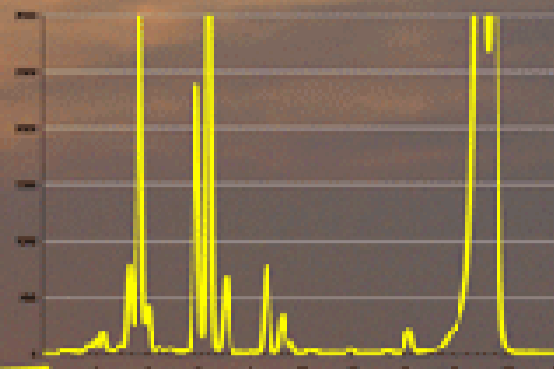


# TXRF 2009 Göteborg Sweden



## We are happy to invite you to Gothenburg, Sweden, to participate in the 13<sup>th</sup> international conference on Total Reflection X-Ray Fluorescence Analysis and Related Methods

June 15-19, 2009

Organised by University of Gothenburg In co-operation with IAEA with the support of EXSA, Bruker and Rigaku.

### Scope of the conference

The aim of the conference is for experts and user of Total Reflection X-ray Fluorescence (TXRF) and related techniques to meet, present and discuss recent advances, research results, novel fields of applications and future directions in the field of TXRF. The conference covers many aspects and applications of TXRF analysis: medical, biological and environmental applications as well as industrial investigations; surface analyses for contamination control and process checking; instrumental and method development and data analysis.

The scope of the conference is not limited to TXRF, but analytical methods and techniques related to TXRF are also discussed. RefLEXAFS, X-Ray Reflectivity, Grazing Incidence X-Ray Fluorescence Analysis, Grazing Exit X-Ray Fluorescence Analysis, X-Ray Standing-wave analysis are examples of such techniques.

Researchers, academics, scientists are invited to attend the meeting and share their work, experience, results and successes but also questions and difficulties to nourish the discussion and let the whole international community profit from it.

### **Welcome!**

Johan Boman conference chair

Please check the home page frequently for updated information about the conference. <http://www2.chem.gu.se/atmo/txrf2009.html>



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